MOSFET – N-Channel, UniFET™

500 V, 48 A, 105 m Ω

FDH50N50, FDA50N50

Description

UniFET MOSFET is ON Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.

Features

- $R_{DS(on)} = 89 \text{ m}\Omega$ (Typ.) @ $V_{GS} = 10 \text{ V}, I_D = 24 \text{ A}$
- Low Gate Charge (Typ. 105 nC)
- Low C_{rss} (Typ. 45 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- These Devices are Pb-Free and are RoHS Compliant

Applications

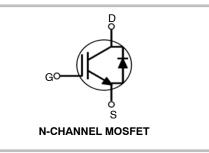
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply

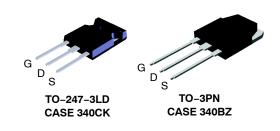


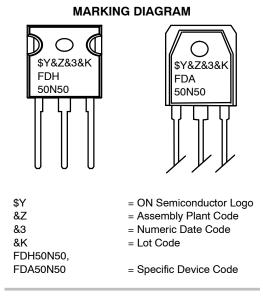
ON Semiconductor®

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V _{DS}	R _{DS(ON)} MAX	I _D MAX
500 V	105 mΩ @ 10 V	48 A







ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

ABSOLUTE MAXIMUM RATINGS (T_C = 25° C unless otherwise noted)

Symbol	Parameter		FDH50N50-F133/ FDA50N50	Unit	
V _{DSS}	V _{DSS} Drain to Source Voltage		500	V	
Ι _D	Drain Current –	–Continuous (T _C = 25°C) –Continuous (T _C = 100°C)		A A	
I _{DM}	Drain Current	-Pulsed (Note 1)	192	А	
V _{GSS}	Gate-Source Voltage		±20	V	
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		1868	mJ	
I _{AR}	Avalanche Current (Note 1)		48	А	
E _{AR}	Repetitive Avalanche Energy (Note 1)		62.5	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		20	V/ns	
P _D	Power Dissipation	(T _C = 25°C) -Derate Above 25°C	625 5	W W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		–55 to + 150	°C	
ΤL	Maximum Lead Temperature for Soldering, 1/8	" from Case for 5 Second	300	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive Rating: Pulse width limited by maximum junction temperature. 2. L = 1.46 mH, I_{AS} = 48 A, V_{DD} = 50 V, R_G = 25 Ω , Starting T_J = 25 °C. 3. $I_{SD} \le 48$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, Starting T_J = 25 °C.

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Mark	Package	Package Method	Reel Size	Tape Width	Quantity
FDH50N50-F133	FDH50N50	TO-247-3	Tube	N/A	N/A	30 Units
FDA50N50	FDA50N50	TO-3PN	Tube	N/A	N/A	30 Units

THERMAL CHARACTERISTICS

Symbol	Parameter	FDH50N50-F133/ FDA50N50	Unit
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	0.2	°C/W
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient, Max.	40	

ELECTRICAL CHARACTERISTICS (T_C = 25° C unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
OFF CHARA	ACTERISTICS					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0 \ V$	500	-	-	V
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C	-	0.5	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 500 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	25	μΑ
		$V_{DS} = 400 \text{ V}, \text{ T}_{C} = 125^{\circ}\text{C}$	-	-	250	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = 20 V, V_{DS} = 0 V	-	-	100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$	-	-	-100	nA
ON CHARA	CTERISTICS					

VG	GS(th)	Gate Threshold Voltage	V_{DS} = V_{GS} , I_D = 250 μ A	3.0	-	5.0	V
R _D	S(on)	Static Drain-Source On-Resistance	V_{GS} = 10 V, I _D = 24 A	-	0.089	0.105	Ω
g	JFS	Forward Transconductance	V _{DS} = 40 V, I _D = 48 A	-	20	-	S

DYNAMIC CHARACTERISTICS

C _{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1 MHz	-	4979	6460	pF
C _{oss}	Output Capacitance		-	760	1000	pF
C _{rss}	Reverse Transfer Capacitance		-	50	65	pF
C _{oss}	Output Capacitance	V_{DS} = 400 V, V_{GS} = 0 V, f = 1 MHz	-	161	-	pF
C _{oss} (_{eff.)}	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	342	-	pF

SWITCHING CHARACTERISTICS

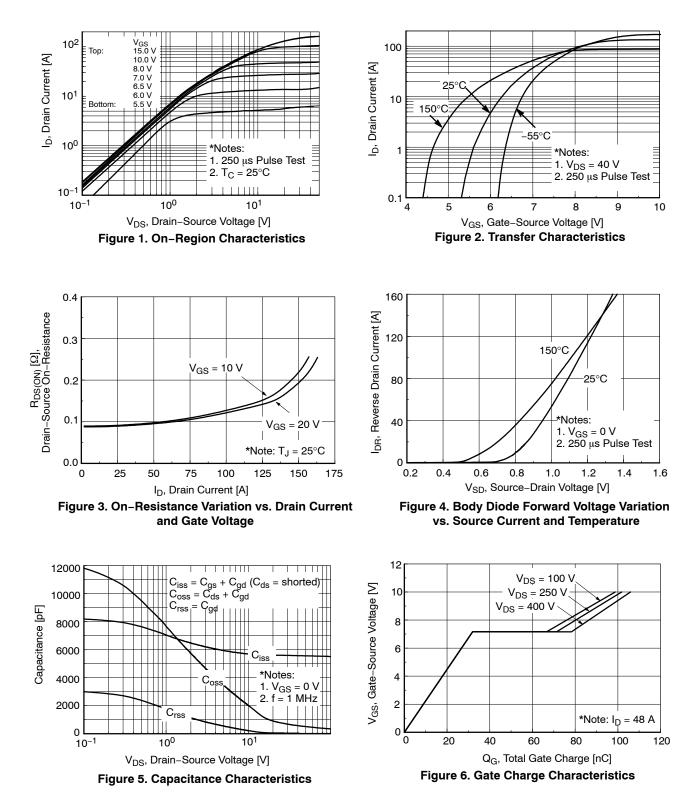
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 250 \text{ V}, \text{ I}_{D} = 48 \text{ A},$	-	105	220	ns
t _r	Turn-On Rise Time	V _{GS} = 10 V, R _G = 25 Ω (Note 4)	-	360	730	ns
t _{d(off)}	Turn-Off Delay Time		_	225	460	ns
t _f	Turn-Off Fall Time]	_	230	470	ns
Qg	Total Gate Charge	V _{DS} = 400 V, I _D = 48 A _, V _{GS} = 10 V	-	105	137	nC
Q _{gs}	Gate-Source Charge	(Note 4)	_	33	-	nC
Q _{gd}	Gate-Drain Charge]`	-	45	-	nC

DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS

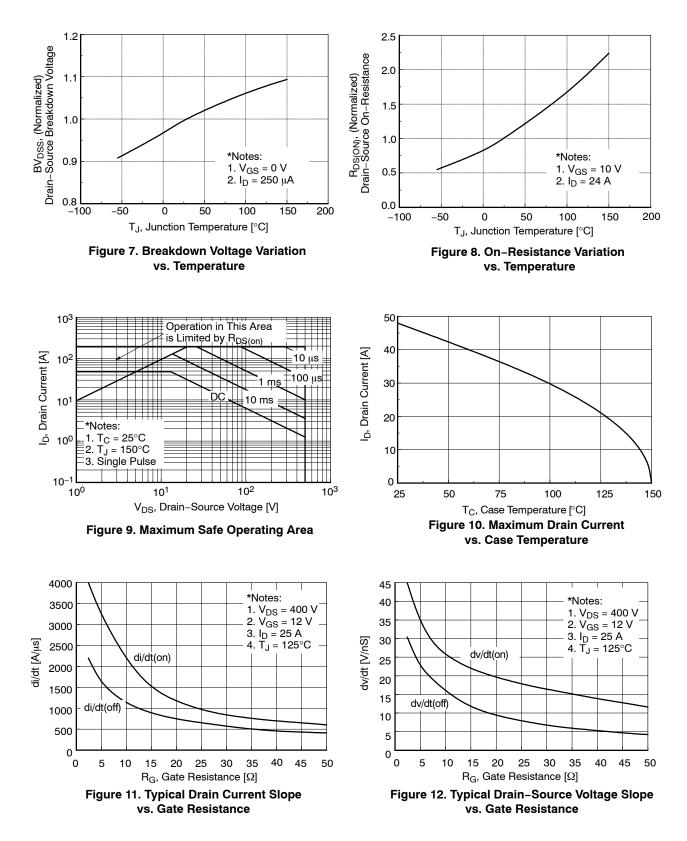
۱ _S	Maximum Continuous Drain-Source Diode Forward Current		-	-	48	А
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		-	-	192	А
V_{SD}	Source to Drain Diode Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{S} = 48 \text{ A}$	-	-	1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 V, I_S = 48 A,$	-	580	-	ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt = 100 Å/µs	-	10	-	μC

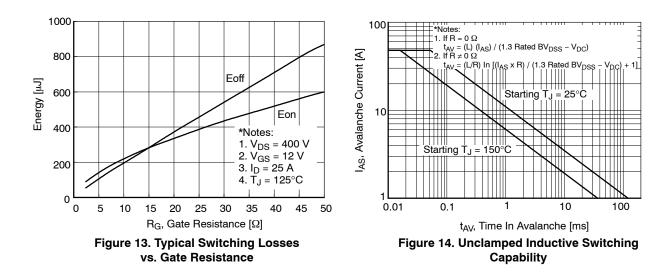
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.Essentially Independent of Operating Temperature Typical Characteristics.

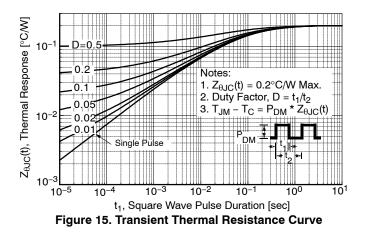
TYPICAL CHARACTERISTICS

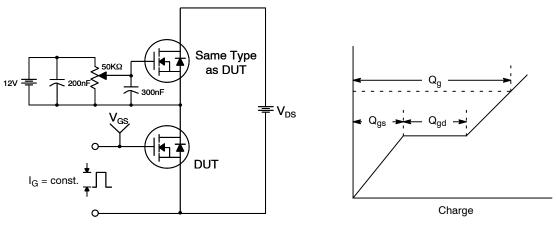


TYPICAL CHARACTERISTICS











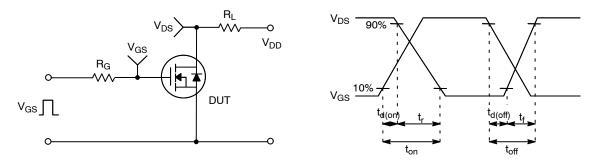


Figure 17. Resistive Switching Test Circuit & Waveforms

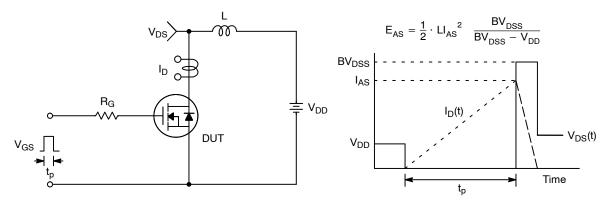


Figure 18. Unclamped Inductive Switching Test Circuit & Waveforms

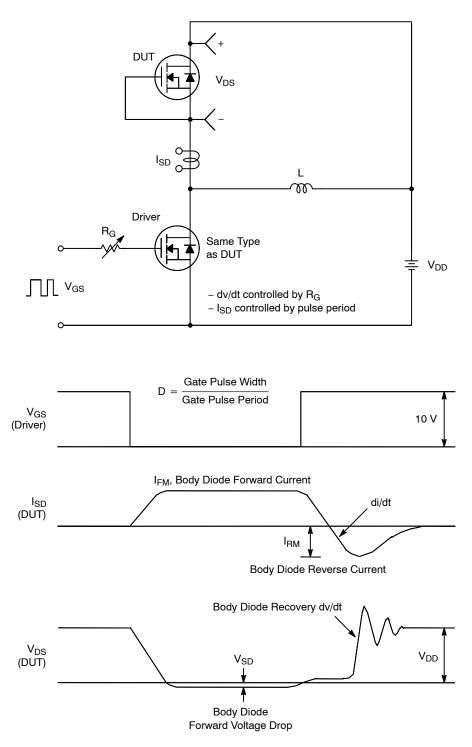
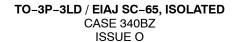


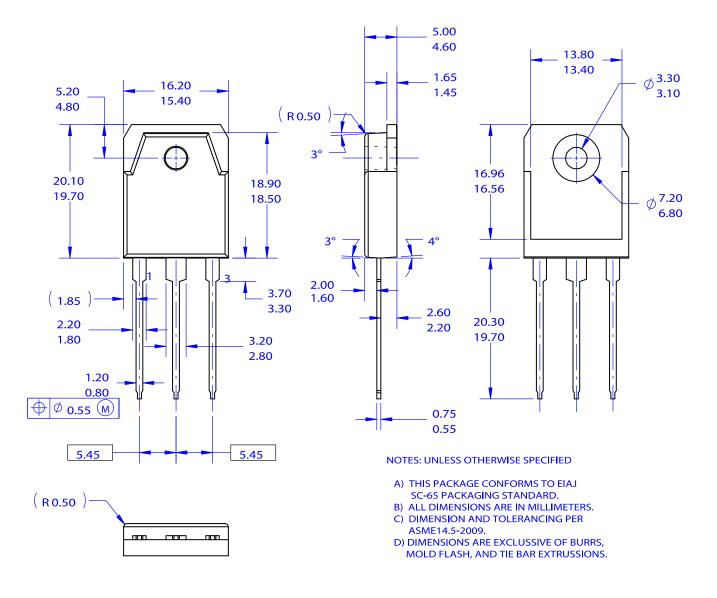
Figure 19. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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